

Analysis of deep level spectrum in GaAs p⁺-p-i-n-n⁺ structures

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Characterization of deep level traps in semiconductor structures using numerical experiments

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Modelling and experimental characterisation of self-regulating resistive heating elements for disposable medical diagnostics devices

Pardy, Tamas; Rang, Toomas; Tulp, Indrek Materials characterization VII 2015 / p. 263-271 : ill

Polytypic heterojunctions for wide bandgap semiconductor materials

Shenkin, Mikhail; Korolkov, Oleg; Rang, Toomas; Rang, Galina Materials characterization VII 2015 / p. 273-282 : ill